# 2SB1317

# Silicon PNP triple diffusion planar type

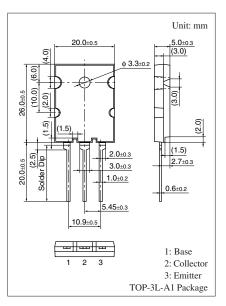
For high power amplification Complementary to 2SD1975

#### Features

- $\bullet$  Excellent collector current  $I_C$  characteristics of forward current transfer ratio  $h_{FE}$
- Wide safe operation area
- $\bullet$  High transition frequency  $f_{\rm T}$
- Optimum for the output stage of a Hi-Fi audio amplifier

| Parameter                             | Symbol              | Rating           | Unit        |    |  |  |  |
|---------------------------------------|---------------------|------------------|-------------|----|--|--|--|
| Collector-base voltage (Er            | V <sub>CBO</sub>    | -180             | V           |    |  |  |  |
| Collector-emitter voltage             | V <sub>CEO</sub>    | -180             | V           |    |  |  |  |
| Emitter-base voltage (Collector open) |                     | V <sub>EBO</sub> | -5          | V  |  |  |  |
| Collector current                     |                     | I <sub>C</sub>   | -15         | А  |  |  |  |
| Peak collector current                | I <sub>CP</sub>     | -25              | А           |    |  |  |  |
| Collector power dissipation           |                     | P <sub>C</sub>   | 150         | W  |  |  |  |
|                                       | $T_a = 25^{\circ}C$ |                  | 3.5         |    |  |  |  |
| Junction temperature                  |                     | Tj               | 150         | °C |  |  |  |
| Storage temperature                   |                     | T <sub>stg</sub> | -55 to +150 | °C |  |  |  |
|                                       |                     |                  |             |    |  |  |  |

#### Absolute Maximum Ratings $T_C = 25^{\circ}C$



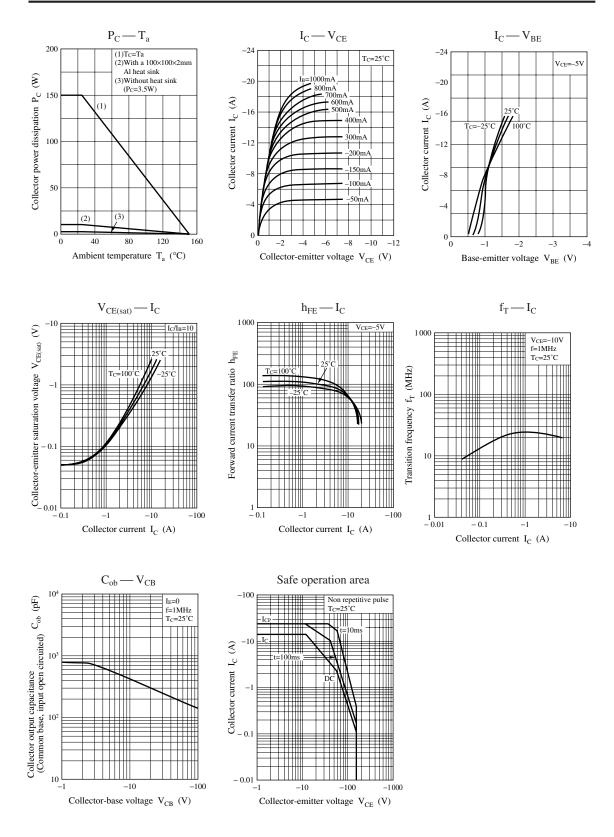
## Electrical Characteristics $T_C = 25^{\circ}C \pm 3^{\circ}C$

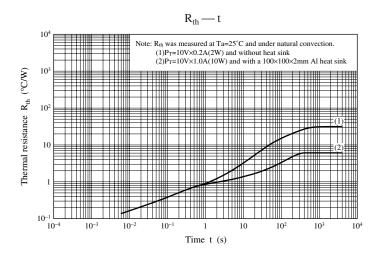
| Parameter                                    | Symbol               | Conditions   | Min | Тур | Max  | Unit |
|--|----------------------|--|-----|-----|------|------|
| Base-emitter voltage                         | V <sub>BE</sub>      | $V_{CE} = -5 V, I_C = -8 A$                                      |     |     | -1.8 | V    |
| Collector-base cutoff current (Emitter open) | I <sub>CBO</sub>     | $V_{CB} = -180 \text{ V}, I_E = 0$                               |     |     | -50  | μΑ   |
| Emitter-base cutoff current (Collector open) | I <sub>EBO</sub>     | $V_{EB} = -3 V, I_C = 0$   |     |     | -50  | μΑ   |
| Forward current transfer ratio               | h <sub>FE1</sub>     | $V_{CE} = -5 \text{ V}, I_C = -20 \text{ mA}$                    | 20  |     |      |      |
|  | h <sub>FE2</sub> *   | $V_{CE} = -5 V, I_C = -1 A$                                      | 60  |     | 200  |      |
|  | h <sub>FE3</sub>     | $V_{CE} = -5 \text{ V}, I_C = -8 \text{ A}$                      | 20  |     |      |      |
| Collector-emitter saturation voltage         | V <sub>CE(sat)</sub> | $I_{\rm C} = -10 \text{ A}, I_{\rm B} = -1 \text{ A}$            |     |     | -2.5 | V    |
| Transition frequency                         | f <sub>T</sub>       | $V_{CE} = -5 \text{ V}, I_C = -0.5 \text{ A}, f = 1 \text{ MHz}$ |     | 20  |      | MHz  |
| Collector output capacitance                 | C <sub>ob</sub>      | $V_{CB} = -10 \text{ V}, I_E = 0, f = 1 \text{ MHz}$             |     | 200 |      | pF   |
| (Common base, input open circuited)          |                      |  |     |     |      |      |

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

2. \*: Rank classification

| Rank             | Q         | S         | Р          |
|------------------|-----------|-----------|------------|
| h <sub>FE2</sub> | 60 to 120 | 80 to 160 | 100 to 200 |





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